

<b>Notice of References Cited</b>	Application/Control No. 10/526,369	Applicant(s)/Patent Under Reexamination KATSUYAMA ET AL.	
	Examiner Nina A. Archie	Art Unit 1645	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0118576	06-2005	Meier et al.	435/006
*	B	US-5,182,195	01-1993	Nakahama et al.	435/69.1
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	WO200120020	03-2001		Bounaga et al	
*	O	WO200268687	09-2002		Naihe et al	
	P					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Bowie et al. (Science, 1990, 247:1306-1310)
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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